11:40 F-54 Development of Quantification Method Using Fundamental Parameter Method for EDXRF
S. Hara, N. Kawahara, T. Matsuo, M. Dei, Rigaku Corporation, Osaka, Japan

12:00 F-59 Characterization of Gemstones by Multiple Excitation EDXRF
M. Holler, Fischer Technology, Windsor, CT
V. Rößiger, Helmut Fischer GmbH, Sindelfingen, Germany
A. Peretti, Gemresearch Swisslab AG, Lucerne, Switzerland
D. Günther, ETH Zürich, Switzerland

THURSDAY PM

XRD & XRF

CULTURAL HERITAGE I (SUPPORTED BY BRUKER)

Chairs: M. Walton, Getty Conservation Institute, Los Angeles, CA
K. Eremín, Harvard Art Museum, Cambridge, MA

2:00 F-19 Invited—Analysis of Meissen Ceramics from the Hoffmeister Collection by HH-XRF
A.J. Shortland, K. Domoney, Cranfield University, Swindon, UK
S. Kuhn, Bonham's Auctioneers, London, UK

2:30 C-8 Invited—Analyzing Stratigraphy with a Dual XRD/XRF Instrument
G. Chiari, Getty Conservation Institute, Los Angeles, CA

3:00 D-3 An Archaeologist's Dilemma
K.D. Rogers, S. Beckett, S. Kuhn, Cranfield University, Swindon, Wiltshire, UK
A. Chamberlain, Sheffield University, Sheffield, UK
J. Clement, University of Melbourne, Melbourne, Australia

3:20 Break

3:50 F-50 Invited—Incorporating the Concept of Secondary Targets in Handheld X-ray Fluorescence to Increase Sensitivity of Minor Elements
C. McGlinchey, The Museum of Modern Art, NY, NY
B. Kaiser, T. Howe, Bruker Elemental, Kennewick, WA

4:20 F-79 Characterization of Silver Gelatin Fiber Based Photographic Papers using X-ray Fluorescence Spectroscopy
P. Messier, LLC, Boston, MA
A. Chapman, University of Delaware Program in Art Conservation, Winterthur, DE

THURSDAY PM

XRD

RIETVELD ANALYSIS II

Chairs: J. Kaduk, Poly Crystallography Inc., Naperville, IL
S.T. Mixture, NYS College of Ceramics at Alfred University, Alfred, NY

2:00 D-74 Invited—High-Resolution Powder X-ray Diffraction Study of Complex Minerals
S.M. Antao, University of Calgary, Calgary, Alberta, Canada